

# TC74HC4024AP, TC74HC4024AF

## 7-Stage Binary Counter

The TC74HC4024A is a high speed CMOS 7-STAGE BINARY COUNTER fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

A negative transition on the  $\overline{CK}$  input brings one increment to the counter.

A CLR input is used to reset the counter to the all low level state. A high level at CLR accomplishes the reset function.

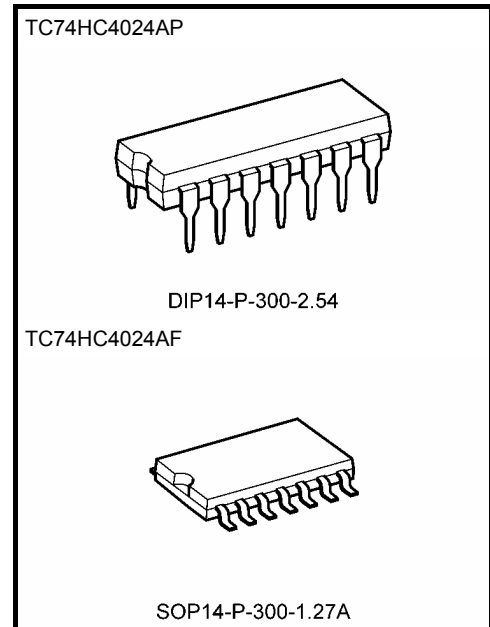
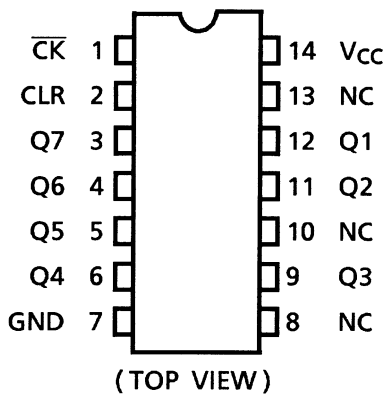
All divided output stages are provided, and the last stage, 1/128 divided frequency will be obtained.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

### Features

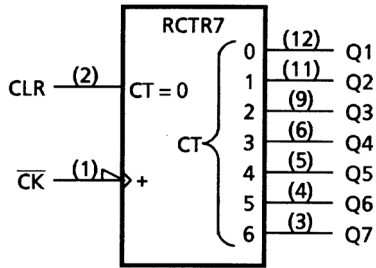
- High speed:  $f_{max} = 70$  MHz (typ.) at  $V_{CC} = 5$  V
- Low power dissipation:  $I_{CC} = 4$   $\mu$ A (max) at  $T_a = 25^\circ$ C
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\%$   $V_{CC}$  (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 4$  mA (min)
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} (opr) = 2\sim 6$  V
- Pin and function compatible with 4024B

### Pin Assignment



Weight	
DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)

## IEC Logic Symbol

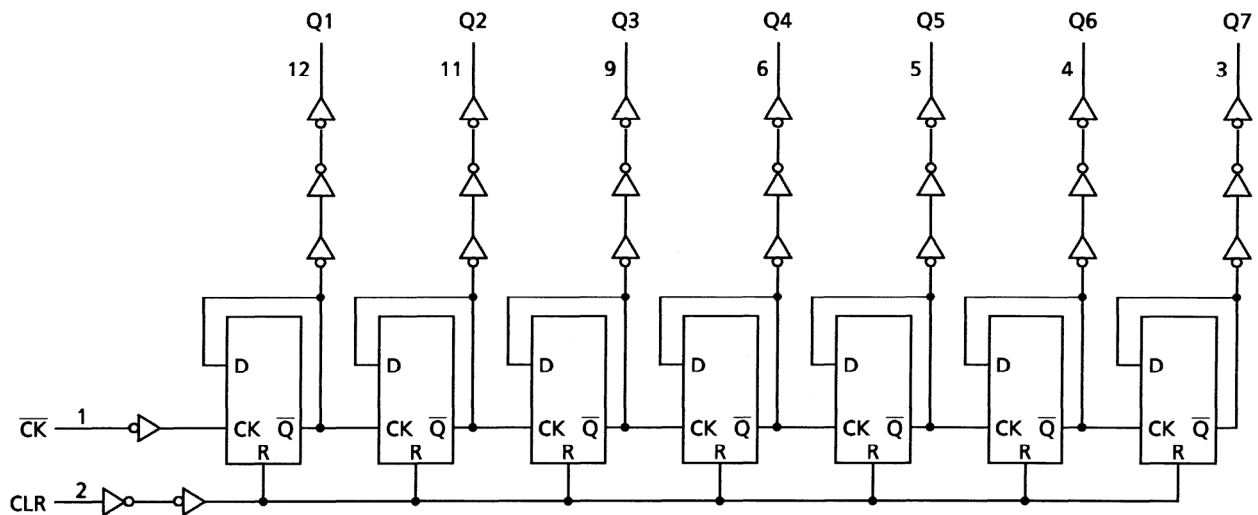


## Truth Table

Inputs		Output Status
CK	CLR	
X	H	All Outputs = "L"
	L	No Change
	L	Advance to Next Stage

X: Don't care

## System Diagram



**Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5~7	V
DC input voltage	$V_{IN}$	-0.5~ $V_{CC} + 0.5$	V
DC output voltage	$V_{OUT}$	-0.5~ $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	$\pm 20$	mA
Output diode current	$I_{OK}$	$\pm 20$	mA
DC output current	$I_{OUT}$	$\pm 25$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 50$	mA
Power dissipation	$P_D$	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	$T_{stg}$	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of  $T_a = -40$  to  $65^\circ\text{C}$ . From  $T_a = 65$  to  $85^\circ\text{C}$  a derating factor of  $-10$  mW/°C shall be applied until 300 mW.

**Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2~6	V
Input voltage	$V_{IN}$	0~ $V_{CC}$	V
Output voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	$t_r, t_f$	0~1000 ( $V_{CC} = 2.0$ V) 0~500 ( $V_{CC} = 4.5$ V) 0~400 ( $V_{CC} = 6.0$ V)	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
				V <sub>CC</sub> (V)	Min	Typ.	Max	Min		Max
High-level input voltage	V <sub>IH</sub>	—		2.0	1.50	—	—	1.50	—	V
				4.5	3.15	—	—	3.15	—	
				6.0	4.20	—	—	4.20	—	
Low-level input voltage	V <sub>IL</sub>	—		2.0	—	—	0.50	—	0.50	V
				4.5	—	—	1.35	—	1.35	
				6.0	—	—	1.80	—	1.80	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20 μA	2.0	1.9	2.0	—	1.9	—	V
				4.5	4.4	4.5	—	4.4	—	
			I <sub>OH</sub> = -4 mA I <sub>OH</sub> = -5.2 mA	4.5	4.18	4.31	—	4.13	—	
				6.0	5.68	5.80	—	5.63	—	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 μA	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
			I <sub>OL</sub> = 4 mA I <sub>OL</sub> = 5.2 mA	4.5	—	0.17	0.26	—	0.33	
				6.0	—	0.18	0.26	—	0.33	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	—	—	4.0	—	40.0	μA

### Timing Requirements (input: t<sub>r</sub> = t<sub>f</sub> = 6 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C		Ta = -40~85°C	Unit	
				V <sub>CC</sub> (V)	Typ.	Limit		Limit
Minimum pulse width ( $\overline{CK}$ )	t <sub>W</sub> (L) t <sub>W</sub> (H)	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum pulse width (CLR)	t <sub>W</sub> (H)	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum removal time	t <sub>rem</sub>	—		2.0	—	25	30	ns
				4.5	—	5	6	
				6.0	—	5	5	
Clock frequency	f	—		2.0	—	6	5	MHz
				4.5	—	31	25	
				6.0	—	36	29	

### AC Characteristics ( $C_L = 15 \text{ pF}$ , $V_{CC} = 5 \text{ V}$ , $T_a = 25^\circ\text{C}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}$ $t_{THL}$	—	—	4	8	ns
Propagation delay time (CK-Q1)	$t_{pLH}$ $t_{pHL}$	—	—	13	20	ns
Propagation delay time ( $Q_n - Q_{n+1}$ )	$\Delta t_{pd}$	—	—	4	9	ns
Propagation delay time (CLR-Qn)	$t_{pHL}$	—	—	13	20	ns
Maximum clock frequency	$f_{max}$	—	34	70	—	MHz

### AC Characteristics ( $C_L = 50 \text{ pF}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	$T_a = 25^\circ\text{C}$			$T_a = -40 \sim 85^\circ\text{C}$		Unit	
			$V_{CC} \text{ (V)}$	Min	Typ.	Max	Min		Max
Output transition time	$t_{TLH}$ $t_{THL}$	—	2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation delay time ( $\overline{\text{CK}} - Q1$ )	$t_{pLH}$ $t_{pHL}$	—	2.0	—	60	120	—	150	ns
			4.5	—	16	24	—	30	
			6.0	—	13	20	—	26	
Propagation delay time ( $Q_n - Q_{n+1}$ )	$\Delta t_{pd}$	—	2.0	—	24	60	—	75	ns
			4.5	—	6	12	—	15	
			6.0	—	5	10	—	13	
Propagation delay time (CLR-Qn)	$t_{pHL}$	—	2.0	—	50	120	—	150	ns
			4.5	—	16	24	—	30	
			6.0	—	13	20	—	26	
Maximum clock frequency	$f_{max}$	—	2.0	6	17	—	5	—	MHz
			4.5	31	63	—	25	—	
			6.0	36	73	—	29	—	
Input capacitance	$C_{IN}$	—	—	5	10	—	10	pF	
Power dissipation capacitance	$C_{PD}$ (Note)	—	—	36	—	—	—	pF	

Note:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

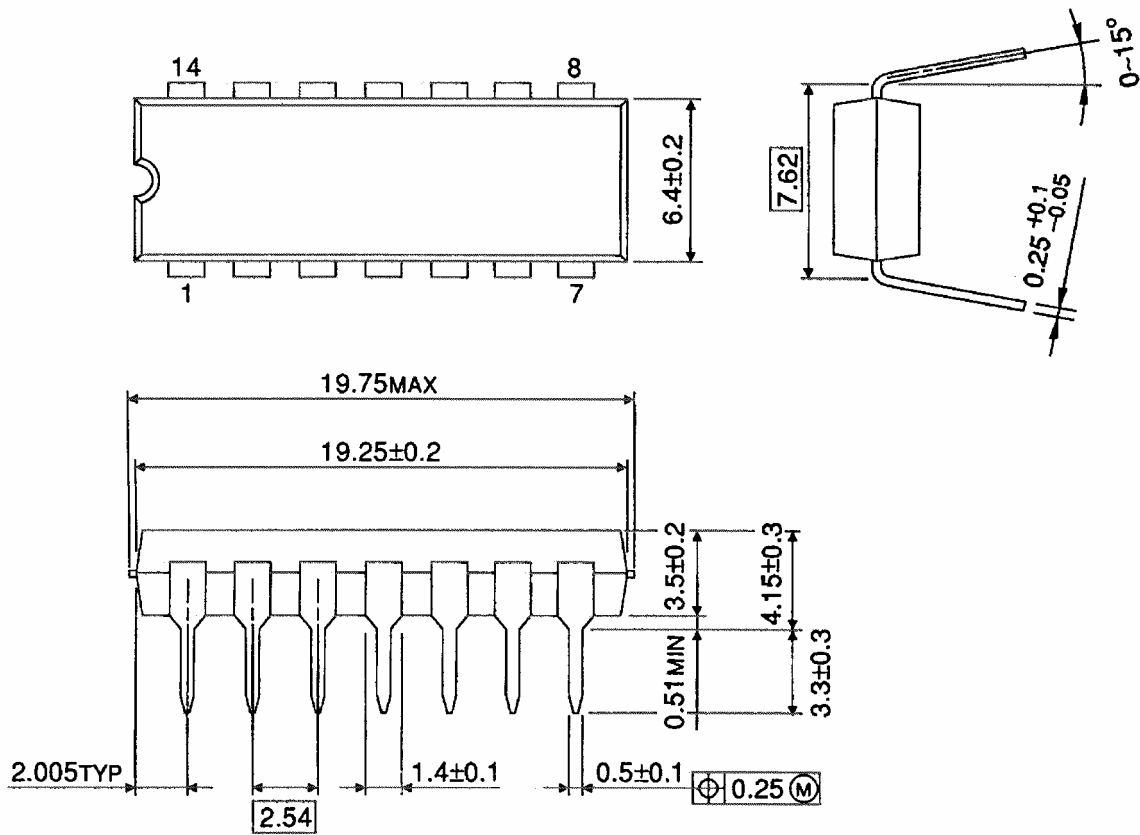
Average operating current can be obtained by the equation:

$$I_{CC} (\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## Package Dimensions

DIP14-P-300-2.54

Unit : mm

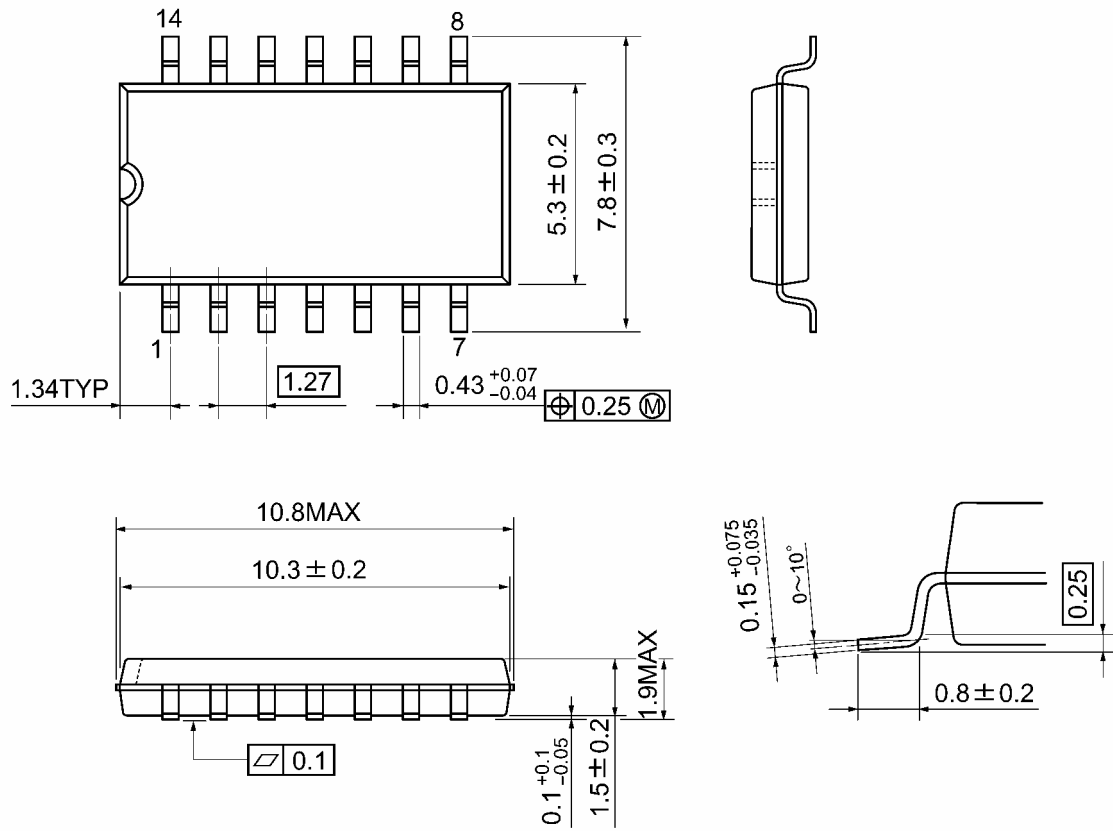


Weight: 0.96 g (typ.)

**Package Dimensions**

SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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